



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al.                      Art Unit : 2815  
Serial No. : 10/799,722                                      Examiner : Edward Wojciechowicz  
Filed : March 15, 2004                                      Confirmation No.: 2070  
Title : HYBRID CIRCUIT AND ELECTRONIC DEVICE USING SAME

MAIL STOP RCE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Supplemental to an information disclosure statement filed December 3, 2004,  
Applications submit herewith a copy of the reference listed on the attached form PTO-1449 and  
its full English language translation.

This filing is being made with the filing of a Request for Continued Examination. No fee  
is required.

Respectfully submitted,

Date: December 28, 2004

  
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Substitute Form PTO-1449

U.S. Department of Commerce  
Patent and Trademark Office

Attorney's Docket No.

07977-221004

Application No.

10/799,722

**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

(37 CFR 1.98(b))

Applicant

Shunpei Yamazaki et al.

Filing Date

March 15, 2004

Group Art Unit

2815

**U.S. Patent Documents**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|-----------------|------------------|----------|-------|----------|----------------------------|
|                  | AA        |                 |                  |          |       |          |                            |
|                  | AB        |                 |                  |          |       |          |                            |
|                  | AC        |                 |                  |          |       |          |                            |
|                  | AD        |                 |                  |          |       |          |                            |
|                  | AE        |                 |                  |          |       |          |                            |
|                  | AF        |                 |                  |          |       |          |                            |
|                  | AG        |                 |                  |          |       |          |                            |
|                  | AH        |                 |                  |          |       |          |                            |
|                  | AI        |                 |                  |          |       |          |                            |
|                  | AJ        |                 |                  |          |       |          |                            |
|                  | AK        |                 |                  |          |       |          |                            |

**Foreign Patent Documents or Published Foreign Patent Applications**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
|                  |           |                 |                  |                          |       |          | Yes         | No |
|                  | AL        | 07-014982       | 01/17/1995       | JAPAN                    |       |          | Full        |    |
|                  | AM        |                 |                  |                          |       |          |             |    |
|                  | AN        |                 |                  |                          |       |          |             |    |
|                  | AO        |                 |                  |                          |       |          |             |    |
|                  | AP        |                 |                  |                          |       |          |             |    |

**Other Documents (include Author, Title, Date, and Place of Publication)**

| Examiner Initial | Desig. ID | Document |
|------------------|-----------|----------|
|                  | AQ        |          |
|                  | AR        |          |
|                  | AS        |          |
|                  | AT        |          |

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.